Activity 8: Noise Analysis

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I. TRANSISTOR NOISE

A. NMOS Noise

For the NMOS with VDS = VGS = 900 mV, $I_D = 439 \mu A$. Additionally, $g_m = 2.44 mS$ and $v^* = 440 mV$ as seen in the image below.

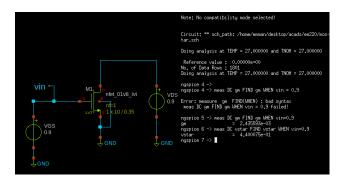


Fig. 1. g_m and v^*

The values are obtained by using the MEAS command. Note that the TT corner is used.

1) Simulations: Flicker noise dominates the range f < 500MHz whereas thermal noise dominates the region where f > 500MHz. With this, the flicker noise corner is at around f = 500MHz.

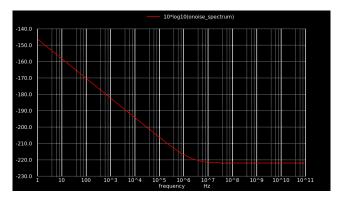


Fig. 2. Output Noise PSD

2) Estimating γ : Recall that in the absence of flicker noise, and assuming $\alpha=1$

$$\overline{i_{od}^2} = 4kT\gamma g_m$$

The total integrated noise power is equal to

$$P_{i,noise} = \int_{f1}^{f2} \frac{i_{od}^2}{i_{od}^2} df$$

$$= \int_{f1}^{f2} 4kT\gamma g_m df$$

$$= 4kT\gamma g_m \cdot (f_2 - f_1)$$

This means that if the integrated output noise power is obtained at the region where thermal noise is dominant, it is possible to directly compute for γ . To estimate, the total output noise power with 1-GHz bandwidth centered at around 90-GHz will be chosen. Since

B. PMOS Noise